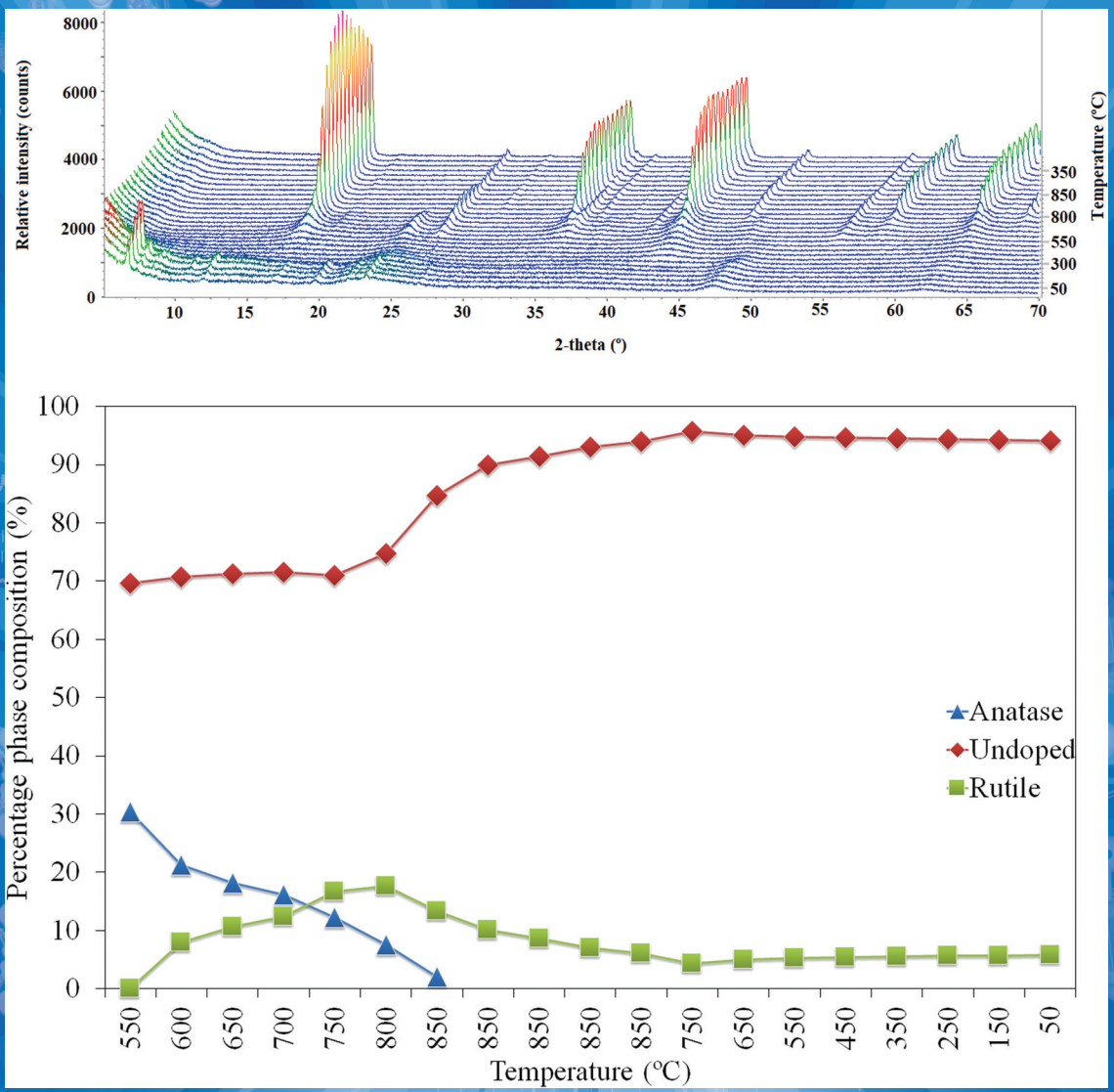
Powder Diffraction PDJ

Journal of Materials Characterization



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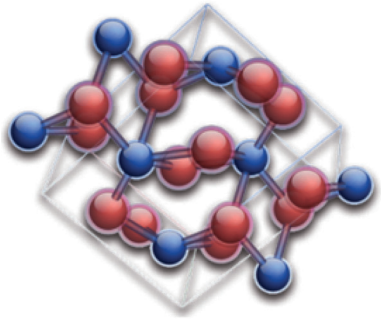

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EDITORIAL

TECHNICAL ARTICLES

NEW DIFFRACTION DATA

CALENDARS OF MEETINGS, SHORT COURSES AND WORKSHOPS

INTERNATIONAL REPORT

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Powder Diffraction

An International Journal of Materials Characterization

On the Cover: The cover figures come from the manuscript "An Investigation into the Temperature Phase Transitions of Synthesized Lithium Titanate Materials Doped with Al, Co, Ni and Mg by in-situ powder X-ray Diffraction" published in this issue of *Powder Diffraction* by X. van Niekerk, E.E. Feng, C. Gelant and D. G. Billing. The phase $Li_4Ti_5O_{12}$ (LTO) and the doped analogues are stated to be promising anode materials for lithium-ion batteries due to its zero-strain electrochemical capability, inherent safety and excellent cyclic performance. The cover shows the variable temperature PXRD scans of $Li_4Ti_5O_{12}$ (LTO) synthesized from a sol-gel precursor (upper) and the percentage phase composition of spinel LTO material, anatase and rutile (lower).

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